



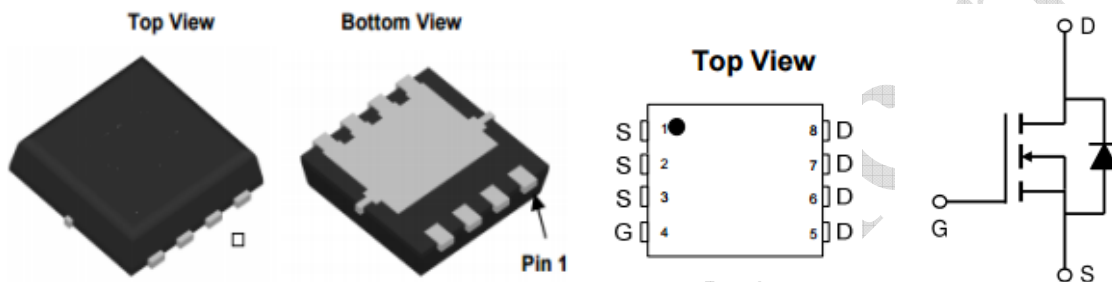
GeneralDescription

The ZLM0307CE combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

RoHS and Halogen-Free Compliant

Product Summary

V_{DS}	-30V
I_D (at $V_{GS}=-4.5V$)	-12A
$R_{DS(ON)}$ (at $V_{GS}=-20V$)	< 10m Ω
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	<14m Ω
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	<20m Ω



Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	-12	A
		-10	
Pulsed Drain Current ^C	I_{DM}	-60	A
Power Dissipation ^B	P_D	3.1	W
		2	
Storage Temperature Range	T_{STG}	-55 to +150	$^{\circ}C$
Operating Junction Temperature Range	T_J	-55 to +150	$^{\circ}C$
Thermal Resistance, Junction-to-Ambient ^A	$R_{\theta JA}$	62	$^{\circ}C/W$

**Electrical Characteristics (T_J=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
$B_{V_{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu A, V_{GS}=0V$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30V, V_{GS}=0V$			-1	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0V, V_{GS}=\pm 20V$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1		-3	V
$I_{D(ON)}$	Onstate drain current	$V_{GS}=-4.5V, V_{DS}=-5V$	-60			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-20V, I_D=-12A$		5	10	m Ω
		$V_{GS}=-10V, I_D=-30A$		7	14	m Ω
		$V_{GS}=-4.5V, I_D=-15A$		14	20	m Ω
g_{FS}	Forward Transconductance	$V_{DS}=-5V, I_D=-10.5A$		27		S
V_{SD}	Diode Forward Voltage	$I_{DS}=-1A, V_{GS}=0V$			-1.2	V
I_S	Maximum Body-Diode Continuous Current				-4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=-15V,$ $f=1MHz$		3500		pF
C_{oss}	Output Capacitance			510		pF
C_{rss}	Reverse Transfer Capacitance			420		pF
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-4.5V, V_{DS}=-10V,$ $I_D=-4A$		33		nC
Q_{gs}	Gate Source Charge			11		nC
Q_{gd}	Gate Drain Charge			13		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=-4.5V, V_{DS}=-10V,$ $R_L=2.5\Omega, R_{GEN}=3\Omega$		8		ns
t_r	Turn-On Rise Time			18		ns
$t_{D(off)}$	Turn-Off Delay Time			78		ns
t_f	Turn-Off Fall Time			42		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-4A, dI/dt=500A/\mu s$		30	40	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-4A, dI/dt=500A/\mu s$		22		nC

Notes:

A. is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θJC} is guaranteed by design while R_{θCA} is determined by the user's board design. R_{θJA} shown below for single device operation on FR-4 in still air.

B. The power dissipation P_D is based on T_{J(MAX)}=150°C, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C. Ratings are based on low frequency and duty cycles to keep initial T_J=25°C.

D. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

E. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T_{J(MAX)}=150°C. The SOA curve provides a single pulse rating.

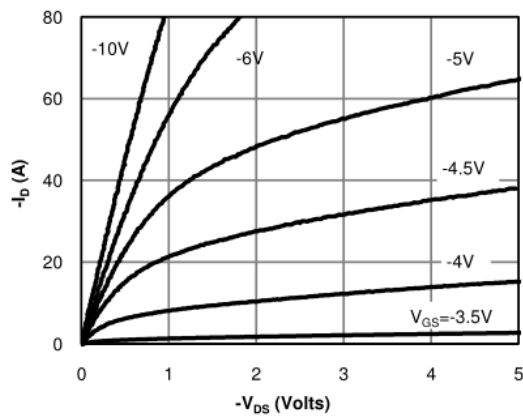
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Fig 1: On-Region Characteristics (Note D)

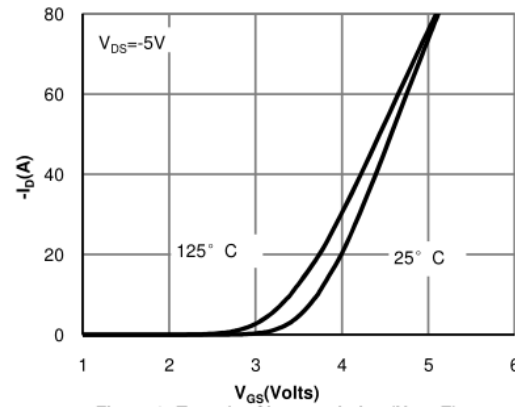


Figure 2: Transfer Characteristics (Note D)

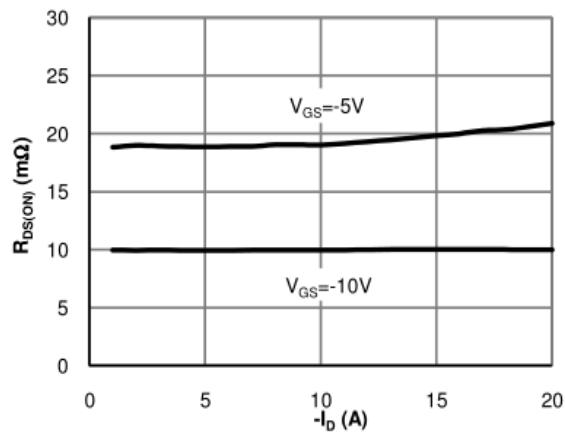


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note D)

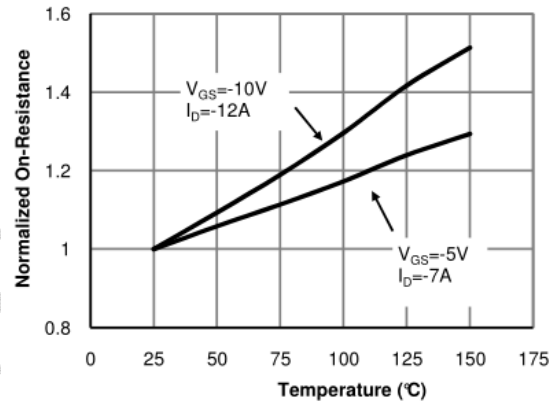


Figure 4: On-Resistance vs. Junction Temperature (Note D)

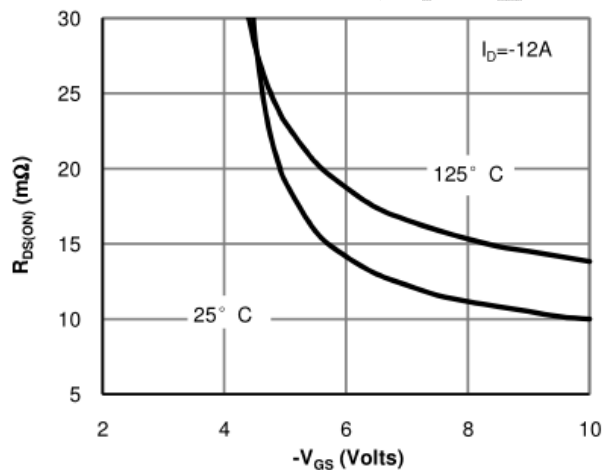


Figure 5: On-Resistance vs. Gate-Source Voltage (Note D)

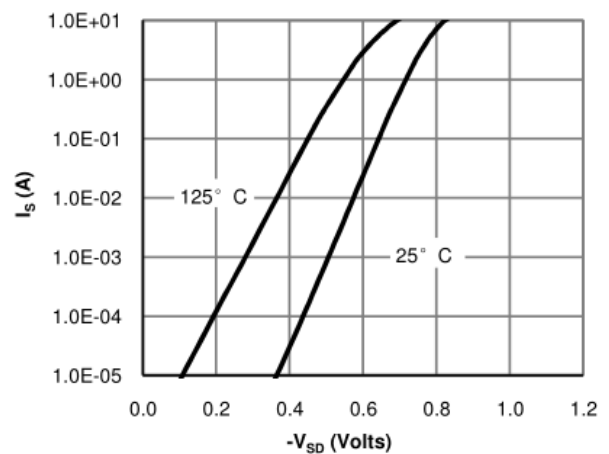


Figure 6: Body-Diode Characteristics (Note D)



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

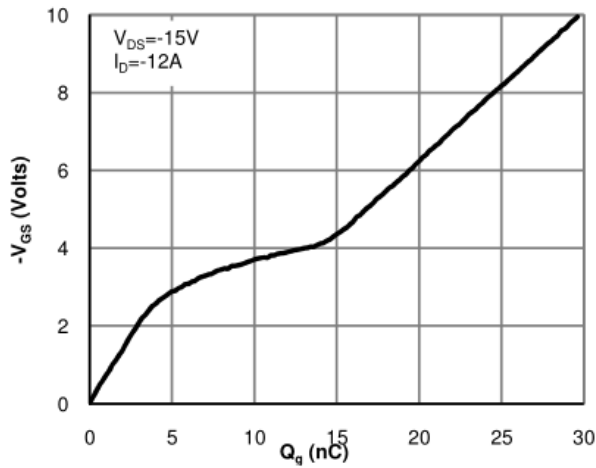


Figure 7: Gate-Charge Characteristics

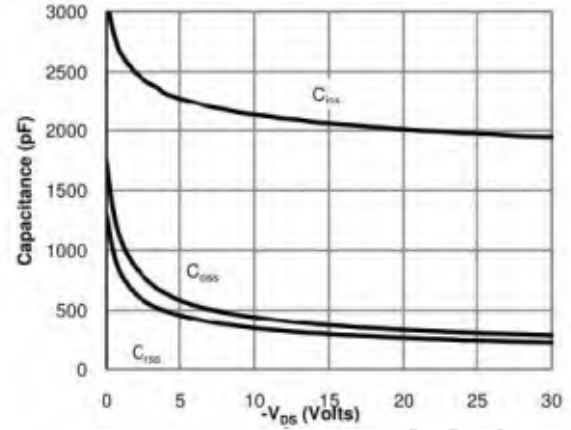


Figure 8: Capacitance Characteristics

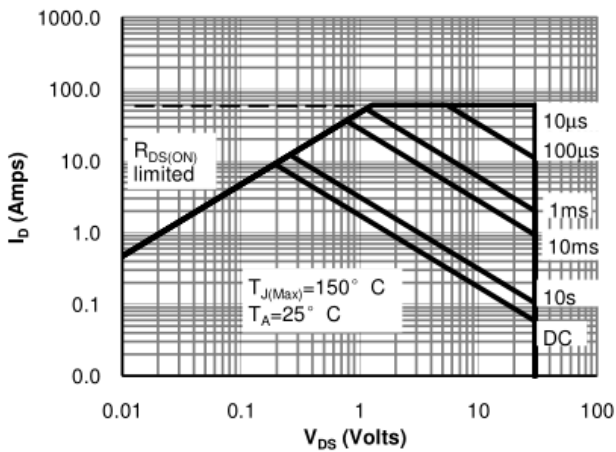


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

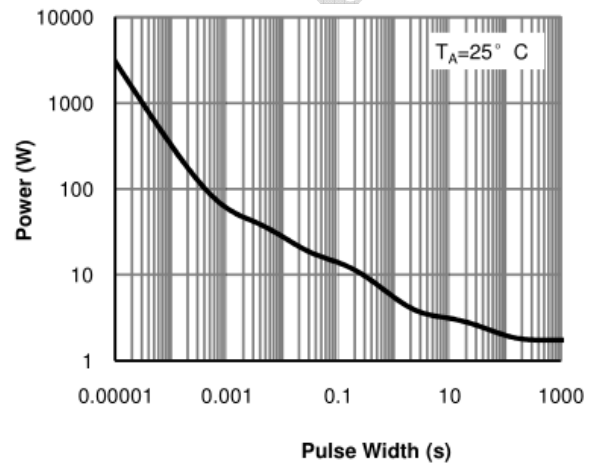


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

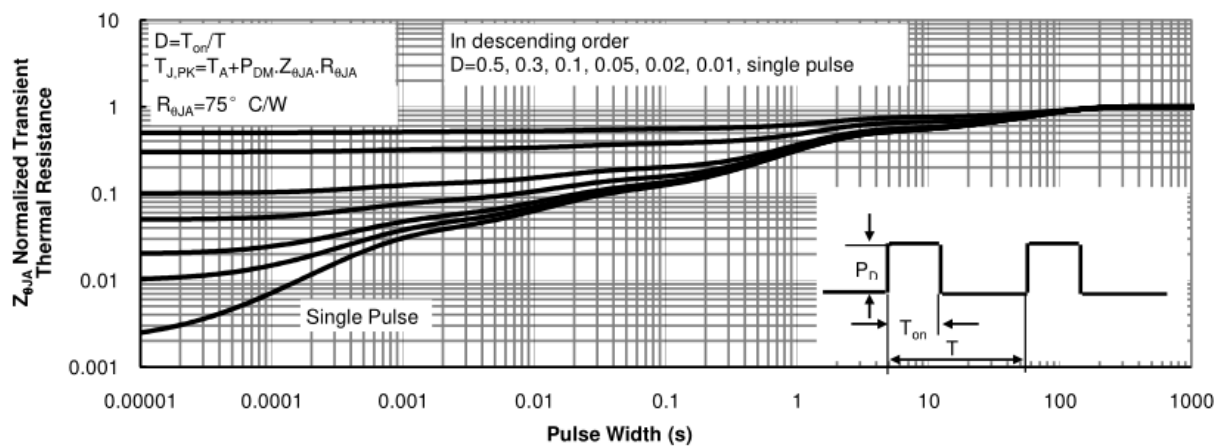
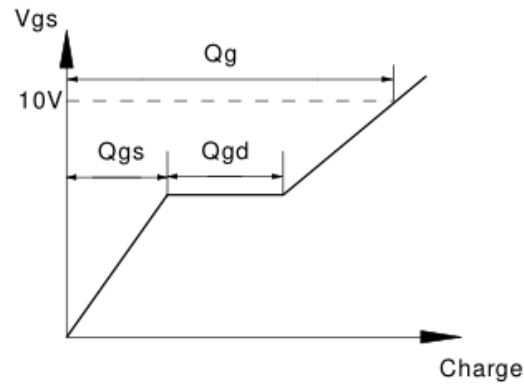
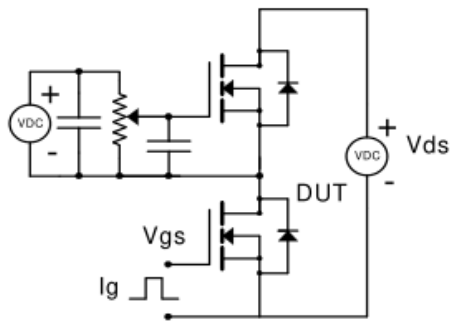


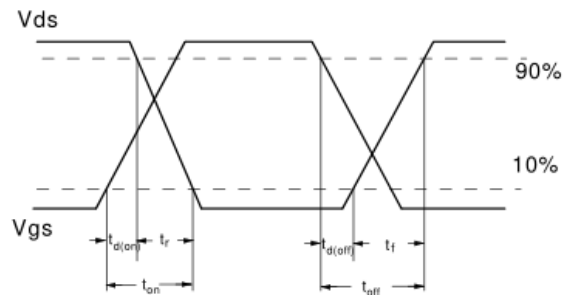
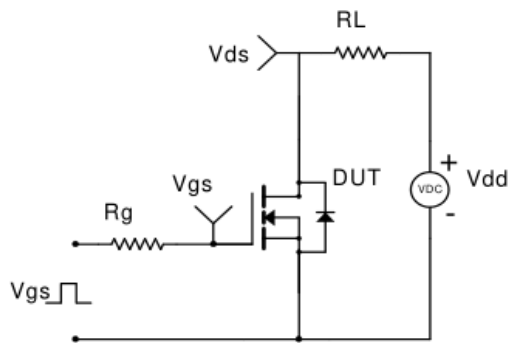
Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)



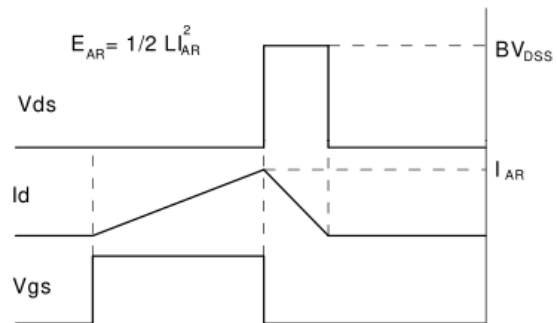
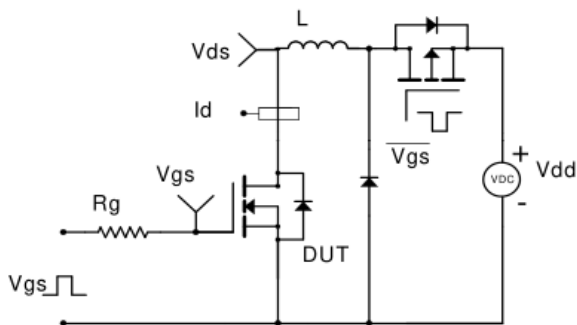
Gate Charge Test Circuit & Waveform



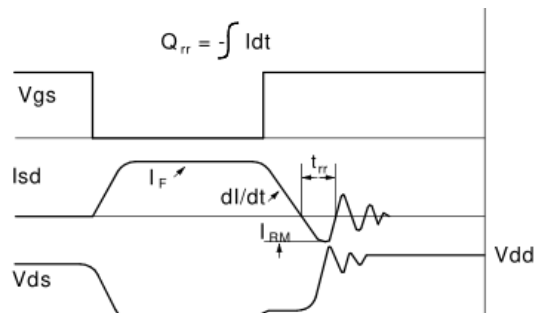
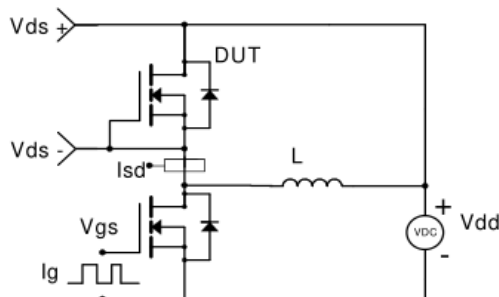
Resistive Switching Test Circuit & Waveforms

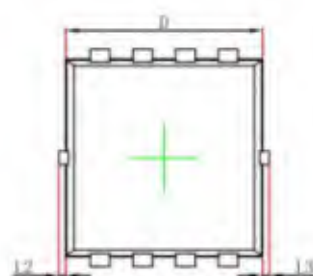


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

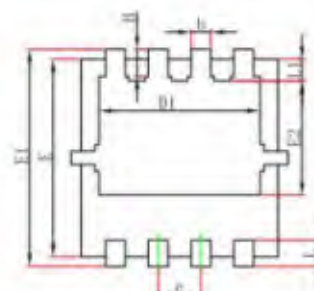


Diode Recovery Test Circuit & Waveforms

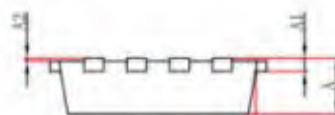


**Package Information****PDFN3*3-8L**

Top view



Bottom view



Side view

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
θ	9°	13°	9°	13°